

PATENT

Atty. Dkt. No. ZIMR/0005

IN THE CLAIMS:

Please cancel claims 17-53.

1.-5. (Cancelled)

6. (Previously Presented) A method for testing of a substrate with several test objects with a test apparatus having a holder for the substrate, a displacement unit for the holder with a holder displacement range in x-direction and a holder displacement range in y-direction, and a contact unit for contacting of the at least one test object, whereby the contact unit has a displacement range in x-direction and/or in y-direction, and the contact unit displacement range in x-direction and/or the contact unit displacement range in y-direction are smaller than the respective holder displacement range, comprising the following steps:

putting the substrate on the holder;

contacting of a first test object with the contact unit, wherein the contact unit has essentially maximal the dimension of half of the holder dimension in one direction perpendicular to the optical axis;

positioning of the substrate so that a first area of the first test object lies in a test range of the test apparatus;

testing of the first area of the test object;

displacing the substrate so that at least a further area of the first test object lies in the test range of the test apparatus;

displacing the contact unit so that the position of the contact unit is essentially unchanged with respect to the first test object;

testing of the further area of the test object; and

displacing the contact unit and the substrate relative to each other so that a further test object can be contacted.

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7. (Previously Presented) The method of claim 6, wherein the contact unit is displaced by tracking.
8. (Previously Presented) The method of claim 6, wherein the contact unit is displaced by carrying along.
9. (Previously Presented) The method of claim 6, wherein the contact unit is displaced as long as a contact to the substrate is present.
10. (Previously Presented) The method of claim 6, wherein the test range is scanned by a beam deflection of a corpuscular beam in two directions.
11. (Previously Presented) The method of claim 6, wherein the test range is scanned by a beam deflection of a corpuscular beam in one direction and a substrate movement in another direction.
12. (Previously Presented) The method of claim 6, wherein the contact unit is displaced as long as no contact to the substrate is present.
13. (Previously Presented) The method of claim 6, wherein the contact unit is adapted to different forms of test objects.
14. (Previously Presented) The method of claim 6, wherein the testing is conducted by scanning of the test range with a corpuscular beam and measurement of the second area electrons.

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15. (Previously Presented) The method of claim 6, wherein the testing is conducted by scanning of the test range with a corpuscular beam and measurement of a signal fed through the contact unit.

16. (Previously Presented) The method of claim 6, wherein before the testing a vacuum of smaller than $1 \cdot 10^{-3}$ mbar is generated.

17-53. (Cancelled)